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E. Ullio
G-20-02

843.41106X00

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): ASAYAMA et al.
Serial No.: Not yet assigned
Filed: On even date
For: SEMICONDUCTOR DEVICE, METHOD OF MEASURING
THE SAME, AND METHOD OF MANUFACTURING THE
SAME



INFORMATION DISCLOSURE STATEMENT
UNDER 37 CFR 1.97 & 1.98

Assistant Commissioner
for Patents
Washington, D.C. 20231

January 22, 2002

Sir:

In the matter of the above-identified application, applicants are submitting herewith a copy of a communication from a foreign patent office in a counterpart foreign application and copies of the documents listed in the attached form equivalent to Form PTO-1449 for the Examiner's consideration.

This information disclosure statement is being submitted with the new application.

To the extent the documents listed on the attached form equivalent to Form PTO-1449 are not in the English language, the requirement of 37 CFR 1.98(a)(3) for a concise explanation of the relevance is satisfied by an English language abstract

of each of the documents provided herewith and the discussion of these documents in the specification, for example, beginning on page 1.

It is respectfully requested that this information disclosure statement be considered by the Examiner.

Please charge any shortage in the fees due in connection with the filing of this paper, including extension of time fees, to the deposit account of Antonelli, Terry, Stout & Kraus Deposit Account No. 01-2135 (843.41106X00) please credit any excess fees to such deposit account.

Respectfully submitted,

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Form PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DKT. NO.	SERIAL NO.
		843.41106X00	Not yet assigned
		INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)	
		APPLICANT	
		ASAYAMA et al.	
		FILING DATE	GROUP
		Jan. 22, 2002	

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date
AA						
AB						
AC						
AD						
AE						
AF						
AG						
AH						

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation /Abstract	
						Yes	No
AI	9-326425	12/16/97	Japan			x	
AJ	9-26436	1/28/97	Japan			x	
AK	8-88258	4/2/96	Japan			x	
AL	8-153763	6/11/96	Japan			x	
AM	9-196970	7/31/97	Japan			x	
AN	54-111286	8/31/79	Japan			x	
AO	11-133061	5/21/99	Japan			x	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

AP	
AQ	
AR	
Examiner	Date Considered

 JC821 U.S. PTO
10/05/05
